Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,304	Y00 ET AL.	
Examiner	Art Unit	
Suk Jin Kang	2619	

SEARCHED				
Class	Subclass	Date	Examiner	
370	208	7/16/2007	SJK	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH:)
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (see attached search strategy)	7/16/2007	sjk
Inventor name and Assignee search in PALM ExPO and EAST	7/16/2007	SJK
Consulted with Chau Nguyen (SPE)	7/16/2007	SJK
Updated Search (see attached search strategy)	1/7/2008	SJK
IEEE Xplore Database	1/7/2008	SJK
Consulted with George Bugg (PE)	1/10/2008	SJK
Consulted with Reinhard Eisenzopf (QAS)	1/10/2008	SJK
Consulted with Chau Nguyen (SPE)	1/14/2008	sJK